

Best Paper Awards

Each year the Design, Automation and Test in Europe Conference presents awards to the authors of the most outstanding papers of the previous year's conference. The selection is performed by an award committee, based on the results of the reviewing process, the quality of the final paper and the quality of the presentation.

The paper selected as the most outstanding in Track D is:

Properties of and Improvements to Time-Domain Dynamic Thermal Analysis Algorithms

*by X Chen and R P Dick, University of Michigan, USA
and
L Shang, University of Colorado at Boulder, USA*

The paper selected as the most outstanding in Track E is:

Skewed Pipelining for Parallel Simulink Simulations

by A Canedo, T Yoshikawa and H Komatsu, IBM Research, Japan

The paper selected as the most outstanding IP is:

Towards a Chip Level Reliability Simulator for Copper/Low-k Backend Processes

by M Bashir and L Milor, Georgia Institute of Technology, USA

Congratulations to the winners!